# Negative piezoelectricity and enhanced electrical conductivity at the interfaces of two-dimensional dialkali oxide and chalcogenide monolayers

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The negative piezoelectric coefficient in ferroelectric polymers has been widely studied. However, the same in the two-dimensional (2D) materials is scarcely reported, which stresses the need for its thorough investigation. Here, the 2D van der Waals (vdW) heterobilayers (vdWHs) of the dialkali metal monochalcogenide  $M_2X$  (M =Na, K, Rb, or Cs; and X = O, S, Se, or Te) monolayers show negative out-of-plane piezoelectricity. Out of all the explored heterobilayers of the family, the maximum piezoelectric strain coefficient in the out-of-plane direction  $d_{33} = -39 \text{ pm V}^{-1}$  is found in the Na<sub>2</sub>Te/Cs<sub>2</sub>S system. This strong piezoelectric coefficient arises from the notable electrostatic potential energy difference and band offset between the constituent monolayers. The small out-of-plane Young's modulus ( $Y \sim 11 \text{ N m}^{-1}$ ), originating from the weak vdW interlayer bonding relative to the stronger intralayer bonding, accounts for the anomalous negative piezoelectricity in the heterostructure. The combination of minute out-of-plane ( $Y = \sim 11 \text{ N m}^{-1}$ ) and in-plane ( $Y = \sim 23 \text{ N m}^{-1}$ ) Young's moduli with small bending modulus (8.83 eV) and negative piezoelectric coefficient underlines the suitability of the proposed vdWH for stretchable and flexible piezotronic devices. Moreover, external perturbations are found to modify the properties of the system. The vertical compressive strain widens the band gap by elevating the conduction band minimum in the heterostructure. An externally applied electric field of low strength (-0.33 and +0.31 V/Å) is found to change the semiconducting heterostructure to metallic upon the closure of the band gap, which is attributed to the dropping of nearly free electron gas (NFEG) states to the Fermi level. A significant enhancement in electrical conductivity has been brought up by the NFEG states upon reaching the Fermi level, which inspires the use of the heterostructure in a nonresistive charge carrier transport application in electronics.

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# I. INTRODUCTION

With the discovery of the remarkable properties of graphene [1], two-dimensional (2D) materials have captured a plenty of attention [2] compared with the bulk materials. The emergence of several unique properties like enormous flexibility, high carrier conductivity, and piezoelectricity [3-6] at the nanoscale has encouraged the futuristic applications of 2D materials. Thus, 2D systems like transition metal dichalcogenides (TMDCs), trichalcogenides, and phosphorene [7-10]have been explored as semiconducting alternatives to pristine zero band gap graphene. While these pristine single layers exhibit different properties relative to their bulk counterparts, there is still ample scope for further improvement to reinforce their properties and enhance their potential in device applications. Consequently, scientific communities have been looking into possibilities to surmount the intrinsic limitations of monolayers and a synergistic combination of their unique properties. One of the avenues for maintaining structural integrity while retaining the critical features of monolayers lies in stacking individual monolayers vertically, forming van der Waals (vdW) heterobilayers [11-13]. The heterobilayers formed predominantly exhibit emergent properties due to interface effects, apart from the properties of the individual

monolayers. Thus, ongoing research focuses on bringing up multifold improvements in 2D materials for their diverse applications in numerous fields [14,15].

The study of piezoelectric response in 2D systems has opened a wide window of opportunities for noncentrosymmetric monolayers in the sector of mechanical energy harvesting, where the ubiquitous mechanical energy in the surroundings can easily be renewed into useful electric energy. A 2D material having broken inversion symmetry, high flexibility, efficiency, and stability can be advantageously exploited for energy harvesting in low-powered devices, vibrationpowered electronics, actuators, flexible or wearable devices, etc. Former investigations on monolayers like TMDCs  $(d_{11} = 3-9 \text{ pm V}^{-1})$  [16], boron binary and ternary V-group monolayers  $(d_{11} = 0.5-4.5 \text{ pm V}^{-1})$  [17], heterostructure MoS<sub>2</sub>/WSe<sub>2</sub> [18], GaN/BP ( $d_{33} = 40 \text{ pm V}^{-1}$ ) [19], Janus transition metal ( $d_{33} = 5-12 \text{ pm V}^{-1}$ ), and Group-IV dichalcogenides [20,21] have revealed positive piezoelectric coefficients in the systems. However, the negative piezoelectric response in 2D systems is scantily detected. In this rarely found piezoelectric property, the material tends to show contraction along the applied electric field (EF) direction, bringing alternative electromechanical functionalities for the system in piezoelectric devices. In earlier studies on negative piezoelectricity in ferroelectric polymers like polyvinylidene difluoride (PVDF) [22] or vdW layered systems like  $CuInP_2S_6$  (CIPS) [23] and bismuth tellurohalides [24], the weak vdW interaction among the interlayers has been

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held responsible for bringing out such an anomalous piezoelectric response in the system. Thus, the current research status warrants further investigation to uncover the possible source of anomalous negative piezoelectricity in 2D monolayers and vdW heterostructures to value additional piezoelectric properties for device applications.

Aside from the inherent features of monolayers, 2D systems respond very well to external stimuli, which can usher in intriguing qualities. Applying external perturbations is understood to be a practical method for improving the properties of 2D monolayers. A viable option for improving the characteristics of 2D monolayers can be comprehended by applying an external EF. The addition of the EF to the system is, in fact, found to bring considerable improvements in the pristine properties such as optical, thermal, adsorption, and band gap tunability of the system [25-28]. In very few materials, the nearly free electron gas (NFEG) states of the vacuum observed descending around the Fermi level through the vertical EF can be readily realized by gating in field-effect transistors [29–31]. These surface states are naturally unoccupied and are present at high energy levels near the vacuum. Moreover, as the NFEG states drop near the Fermi level, a significant boost in the catalytic activity, surface chemistry, and electrical conductivity can be expected through the availability of a large density of states (DOS) around the Fermi level. The latter is addressed in this paper, as it can significantly improve the performance of the device. Therefore, a comprehensive investigation of these states in 2D systems is crucial, as it obviates the need for resorting to the standard practices, such as doping, surface chemistry, and electrode design [32] for the purpose of enhancing or controlling electrical conductivity and catalytic activities. Moreover, it underscores the need to unveil the essential mechanism underlying the electric-field-induced shifting of NFEG states to near the Fermi level and its effects on electrical conductivity and catalytic activities.

In this paper, an insightful study on the 2D stable family of dialkali metal monochalogenide monolayers  $M_2X$  (M = Na, K, Rb, or Cs; and X = O, S, Se, or Te) and their van der Waal heterostructures has been systematically conducted. The intrinsic properties of monolayers, which include electronic, mechanical, and piezoelectric properties, have been theoretically investigated. The elastic properties revealed a high level of flexibility in the noncentrosymmetric  $M_2X$  monolayers, which motivated the exploration of their piezoelectric properties. Relative to the monolayers, the vdW heterostructures of the family showed an ample piezoelectric response. Colossal negative piezoelectricity in the Na2Te/Cs2S vdW heterostructure has been found. Thus, a detailed analysis of the peculiar negative piezoelectricity observed in the proposed 2D vdW heterostructure has been conducted for the purpose of unveiling its origin. Moreover, the external perturbations, for instance, external vertical strain and EF, are treated on the Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure. Widening of the band gap is noticed with the compressive strain along the z direction. The gradual lowering and closure of the band gap by the normal EF, observed in this paper, is found to arise due to the shifting of NFEG states to the proximity of the Fermi level. The occurrence of NFEG states near the Fermi level influenced and boosted the electric conductivity in the heterostructure, which

has been appropriately addressed in this paper. These findings can enable the application of the heterostructure in lowpowered logic gate devices. In this paper, we aim to provide valuable insights into Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure capabilities and thereby promote the designing of electromechanical, data storage, and enhanced electrical conductivities in devices built from the multifunctional vdW heterostructure.

#### **II. COMPUTATIONAL DETAILS**

First-principles density functional theory (DFT) implemented in the Vienna Ab initio Simulation Package (VASP) [33-36] is employed in this paper. The core electrons and exchange-correlation energy of the electrons are calculated using the projector augmented-wave potentials [37] and the Perdew, Burke, and Ernzerhof (PBE) generalized gradient approximation (GGA) [38,39]. The cutoff energy is set to be 500 eV for the plane-wave basis in the supercells and the convergence of total energy differences of two self-consistent cycles to be  $< 10^{-4}$  eV. The atomic coordinates of the supercells are relaxed until the atomic forces reach < 0.01 eV/Å. The vacuum thickness > 20 Å is preferred to eliminate the periodic images along the z direction. With the inaccuracy in the PBE-optimized band gap calculation, hybrid functional calculations (HSE06) [40,41] are adopted to obtain more precise band gap and band edges for the systems. For the heterostructures, the vdW interactions are implemented by DFT-D3 proposed by Grimme et al. [42,43]. The Brillouin zone sampling is performed via the  $18 \times 18 \times 1$   $\Gamma$ -centered k-mesh for the supercells. The mixing parameter and the range separation parameter are set to 0.25 and 0.2  $A^{-1}$ , respectively. The phonon dispersion is obtained on a  $4 \times 4 \times 1$ supercell for the monolayers using PHONOPY code, built on the density functional perturbation theory (DFPT) method. The BOLTZTRAP2 package is utilized to investigate the electronic transport properties, which is based on the semiclassical Boltzmann transport equation within the constant relaxation time approximation [44]. A linear dipole correction is employed to get around the possible errors emanating from the out-of-plane EF and polarization brought about by the periodic boundary conditions [45]. An external EF application is simulated through a planar dipole sheet introduced at the center of the supercell, as proposed by Neugebauer and Scheffler [46], and implemented in VASP. However, the atomic positions are held fixed under the EF application, which is consistent with earlier works [47-49]. Moreover, Ghosh et al. [50] have demonstrated that the structural parameters, i.e., bond length, bond angle, and buckling height, in bilayer blue phosphorous are barely altered by the externally applied EF and interplanar spacing changes by < 4%; however, significant changes in the electronic properties were found under EF applied within the range of 0-0.5 V/Å. The structural modifications are investigated in this paper for the upper limits of the positive and negative EFs. Minor changes are noticed at the strongest positive EF applied, when the structure is allowed to relax, and are not found to change the physics and the understanding. The corresponding results are presented in the Supplemental Material (SM) [51].

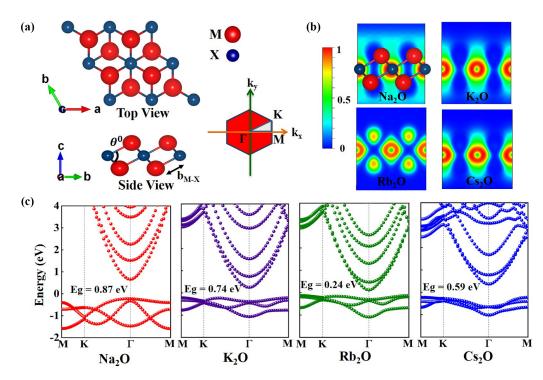


FIG. 1. (a) Top and side views of dialkali monochalcogenides  $M_2X$ , where M = Na, K, Rb, or Cs; and X = O, S, Se, or Te. The  $b_{M-X}$  and  $\theta^{\circ}$  represent the bond length and the bond angle of the monolayers. (b) Electron localization plot for  $M_2O$  (M = Na, K, Rb, and Cs) monolayers. (c) Band dispersion of dialkali monoxide monolayers  $M_2O$  (M = Na, K, Rb, and Cs) using the GGA-PBE exchange-correlation functional.

# **III. RESULTS AND DISCUSSION**

#### A. Relaxed structure of $M_2X$ monolayers

The family comprising 16 monolayers of dialkali metal monochalcogenides  $M_2X$  (alkali metal M = Na, K, Rb, or Cs; and chalcogen X = O, S, Se, or Te) is explored in this paper. The primitive unit cell is arranged in an M-X-M pattern with  $D_{3h}$  point group symmetry in the  $P\bar{6} m^2$  space group. Figure 1(a) shows the top and side views of the hexagonal honeycomb lattice structure of  $M_2X$  monolayers, while Table I lists the relaxed lattice constant, bond length, and bond angle. The lattice parameters are found to be comparable with the earlier reported ones [52,53]. The increase in the bond length and bond angle corresponds with the increasing lattice constant of the  $M_2X$  monolayers containing heavier X. The nature of bonding is detected using the electron localization function (ELF), shown in Fig. 1(b). The red, green, and blue regions correspond to maximum (100%), average (50%), and least/zero (0%) probability of tracking the electrons in the region. The maximum (minimum) accumulation on the chalcogen atom (alkali metal), which is negligible on the interatomic distribution, reflects the ionic nature of bonding in the  $M_2X$  monolayers. To assure the dynamic stability of the monolayers, the phonon spectra have been inspected. The stability of all the monolayers is shown in Fig. S1 in the SM [51]. Except for a small negative frequency patch near the  $\Gamma$  point, no definite imaginary mode is detected in the Brillouin zone. This small pocket of imaginary frequency is shown by the acoustic flexural (ZA) mode around the  $\Gamma$  point in the phonon spectra. It is a mere artifact in 2D materials, and in some cases, it completely disappears. Reaching numerical

convergence for the ZA phonon mode is a common issue in *ab initio* calculations on 2D materials. Small negative frequency pockets (< 0.3 THz or 10 cm<sup>-1</sup>) around the  $\Gamma$  point caused by ZA modes have also been observed in graphene, silicone, MoS<sub>2</sub>, GeSe [54], and indium chalcogenides [55]. This region of instability is especially sensitive to simulation parameters like supercell size and k-point sampling. For these reasons,

TABLE I. The lattice constant (a, b), bond length  $b_{M-X}$  of chalcogenide with the alkali metal atom, bond angle  $\theta^{\circ}$ , work function  $\phi$  (eV), and band gap  $E_g$  (HSE) in eV of the monolayers in the primitive cell.

Monolayer	a = b (Å)	$b_{M-X}$ (Å)	$ heta^\circ$	$\phi$ (eV)	$E_g$ (HSE)
Na <sub>2</sub> O	3.69	2.31	106.00	3.16	1.94
$Na_2S$	4.45	2.74	108.55	4.13	2.92
Na <sub>2</sub> Se	4.67	2.87	108.95	4.23	2.84
Na <sub>2</sub> Te	5.03	3.07	109.86	4.35	2.86
$K_2O$	4.14	2.65	102.38	2.02	1.25
$K_2S$	4.97	3.11	105.83	3.32	2.46
K <sub>2</sub> Se	5.17	3.23	106.09	3.20	2.27
K <sub>2</sub> Te	5.53	3.45	106.60	3.54	2.55
$Rb_2O$	3.33	2.70	95.20	1.65	0.83
$Rb_2S$	4.44	3.19	101.23	2.53	1.88
Rb <sub>2</sub> Se	4.62	3.20	104.87	2.89	2.20
Rb <sub>2</sub> Te	4.82	3.50	101.12	3.09	2.34
$Cs_2O$	4.27	2.89	95.05	1.93	1.23
Cs <sub>2</sub> S	5.20	3.38	100.36	2.43	1.75
Cs <sub>2</sub> Se	5.42	3.51	100.69	1.33	1.64
Cs <sub>2</sub> Te	5.87	3.74	103.23	2.52	1.98

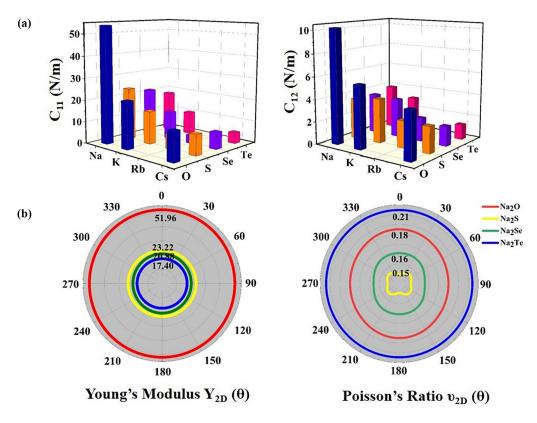


FIG. 2. (a) Elastic constants of  $M_2X$  monolayers and (b) the polar plot of Young's modulus  $Y_{2D}(\theta)$  and Poisson's ratio  $v_{2D}(\theta)$  of disodium monochalcogenide Na<sub>2</sub>X (X = O, S, Se, or Te) monolayers.

the negative frequencies are understood to be spurious. Thus, these instabilities are ignorable and thereby confirm the dynamic stability of the monolayers.

The electronic band dispersion for oxide monolayers  $M_2O$ (M = Na, K, Rb, or Cs) is calculated using the GGA-PBE functional, as shown in Fig. 1(c), whereas the other monolayers are provided in Fig. S2 in the SM [51]. As the PBE functional expresses the correct band dispersion while underestimating the band gap, a more precise semiconducting band gap energy is attained through the HSE06 functional for all the monolayers and is presented in Table I. Also, the work function for the monolayers has been tabulated in Table I to provide a zeroth-order estimation of the band alignment. From the band spectra given in Fig. 1(c), the primarily parabolic conduction band minimum (CBM) and flat valence band maximum (VBM) dispersion is observed, which would set the lighter electron and bulkier hole mass in the monolayers. The  $Na_2X$  monolayers showed a direct band gap, while the higher alkali monolayers  $M_2X$  (M = K, Rb, or Cs) presented an indirect band gap. The relocating of the VBM from the  $\Gamma$  point toward the K point has resulted in an indirect band gap in the systems. It has been shown in a prior investigation that the strong *p*-orbital hybridization between the higher alkali metal and chalcogenide atoms caused the shifting of the VBM and changed the band gap from direct to indirect [52].

### B. Mechanical stability and properties

The elastic constants quantify the stiffness of a material. A stiffer material retains its shape for a larger magnitude of applied force or strain. In such cases, a material with less stiffness or smaller Young's modulus (i.e., more flexibility or stretchability) is suitable for flexible electronics. The values of in-plane elastic constants for monolayer  $M_2X$  are presented in the bar graph plot in Fig. 2(a). Here, both the ionic and electronic contributions have been summed in the elastic stiffness coefficients. From the elastic constant, all the monolayers of the family are found to be highly flexible. The elastic constants are found to decrease with the higher chalcogen monolayer from O to Te and higher alkali group from Na to Cs in the monolayers. The mechanical stability has been affirmed based on elastic constants of the monolayers. The Born-Huang stability criteria [56] for the hexagonal systems use the following conditions:

$$C_{11} > |C_{12}|, \quad C_{22} > 0, \quad C_{11}C_{22} - C_{12}^2 > 0, \quad C_{66} > 0.$$
 (1)

All the monolayers entirely satisfy the criteria except for Rb<sub>2</sub>O and Rb<sub>2</sub>Te monolayers. Thus, for the stable systems, the static in-plane Young's modulus ( $Y_{2D}$ ) and Poisson's ratio ( $v_{2D}$ ) have been calculated through the following expressions:

$$Y_{\rm 2D} = \frac{C_{11}^2 - C_{12}^2}{C_{11}},$$
 (2)

$$v_{\rm 2D} = \frac{C_{12}}{C_{11}}.$$
 (3)

The static in-plane Young's modulus and Poisson's ratio have been charted in Table S1 in the SM [51]. Young's modulus shows the utmost flexibility of the monolayers as compared with the extensively studied graphene ( $Y_{2D} = 341 \text{ N m}^{-1}$ ) [57], MoS<sub>2</sub> ( $Y_{2D} = 130 \text{ N m}^{-1}$ ) [58,59], and h-BN ( $Y_{2D} = 275.9 \text{ N m}^{-1}$ ) [60]. The values are comparable with Young's modulus of silicene (61 N m<sup>-1</sup>), Janus SnSSe (57.5 N m<sup>-1</sup>), and germanene (41 N m<sup>-1</sup>) [61]. Poisson's ratios detected are < 0.5, which attested the feasible compressibility of the monolayers.

The orientational Young's modulus  $Y_{2D}(\theta)$  and Poisson's ratio  $v_{2D}(\theta)$  are investigated to find the nature of mechanical properties in the system, using the following relations [62]:

$$Y_{\rm 2D}(\theta) = \frac{C_{11}C_{22} - C_{12}^2}{C_{11}s^4 + C_{22}c^4 + \left(\frac{C_{11}C_{22} - C_{12}^2}{c^2} - 2C_{12}\right)c^2s^2},$$
 (4)

$$v_{2D}(\theta) = \frac{C_{12}(s^4 + c^4) - \left(C_{11} + C_{22} - \frac{C_{11}C_{22} - C_{12}^2}{C_{66}}\right)c^2s^2}{C_{11}s^4 + C_{22}c^4 + \left(\frac{C_{11}C_{22} - C_{12}^2}{C_{66}} - 2C_{12}\right)c^2s^2},$$
 (5)

where *s* and *c* are  $\sin\theta$  and  $\cos\theta$ , and  $\theta$  is the polar angle along the armchair axis. The orientation-dependent plot presented in Figs. 2(b) and S3 in the SM [51] confirms the isotropy in Young's modulus  $Y_{2D}(\theta)$  of Na<sub>2</sub>X (X = O, S, Se, or Te) and other monolayers of the family, which is quite observable in hexagonal symmetry structures [63]. Also, Poisson's ratio  $\nu_{2D}(\theta)$  is found to be quite isotropic except for a little anisotropy in Na<sub>2</sub>S and K<sub>2</sub>Se.

#### C. Piezoelectricity

With the broken inversion symmetry and high flexibility of the monolayers, piezoelectricity is expected to arise. The piezoelectric tensor coefficients have been determined using DFPT integrated into VASP. The  $e_{ij}$  piezoelectric stress tensor is attained by the summation of the ionic and electronic terms  $e_{ij}^{\text{ionic}}$  and  $e_{ij}^{\text{electronic}}$ , respectively.

A three-rank piezoelectric stress tensor  $e_{ijk}$  is expressed as

$$e_{ijk}^{\text{elec}} + e_{ijk}^{\text{ion}} = \left(\frac{\partial P_i}{\partial \varepsilon_{jk}}\right)_{E,T},$$
 (6)

and a three-rank piezoelectric strain tensor  $d_{ijk}$  as

$$d_{ij}^{\text{elec}} + d_{ij}^{\text{ion}} = \left(\frac{\partial P_i}{\partial \sigma_{jk}}\right)_{E,T},\tag{7}$$

where  $E_i$ ,  $P_i$ ,  $\varepsilon_{jk}$ , T, and  $\sigma_{jk}$  are the macroscopic EF, electric polarization, strain tensor, the temperature in Kelvin, and stress tensor. Here, *i*, *j*, and *k* represent the *x*, *y*, and *z* or 1, 2, and 3 directions. The piezoelectric tensors can be correlated as

$$e_{ijk} = \frac{\partial P_i}{\partial \varepsilon_{ik}} = \frac{\partial P_i}{\partial \sigma_{mn}} \frac{\partial \sigma_{mn}}{\partial \varepsilon_{ik}} = d_{imn} C_{mnjk}.$$
 (8)

The  $D_{3h}$  point group symmetric structures do not maintain the exclusiveness of the piezoelectric tensor coefficient. In this case, employing Voigt notation for the 2D materials, the thirdrank piezoelectric tensors can be reduced to second rank by the contraction of the cartesian coordinates as  $11 \rightarrow 1, 22 \rightarrow$  $2, 33 \rightarrow 3, 23 \rightarrow 4, 13 \rightarrow 5$ , and  $12 \rightarrow 6$ , resulting in a

TABLE II. Piezoelectric stress coefficient ( $e_{33}$ ), elastic stiffness constants ( $C_{33}$ ), and out-of-plane piezoelectric strain coefficient ( $d_{33}$ ) of dialkali metal monochalcogenide monolayers.

2D monolayer	$e_{33} (pC m^{-1})$	$C_{33}$ (N m <sup>-1</sup> )	$d_{33} \ ({\rm pm} \ {\rm V}^{-1})$
Na <sub>2</sub> O	21.61	1.751	1.45
Na <sub>2</sub> S	0.00	0.192	0.00
Na <sub>2</sub> Se	0.00	0.133	0.00
Na <sub>2</sub> Te	-0.51	0.52	-1.09
K <sub>2</sub> O	-0.19	1.694	-0.11
K <sub>2</sub> S	0.05	0.129	0.2
K <sub>2</sub> Se	0.05	0.016	-2.8
K <sub>2</sub> Te	0.03	0.027	-1.5
Rb <sub>2</sub> S	-0.03	0.063	-0.51
Rb <sub>2</sub> Se	-0.03	0.054	-0.63
Cs <sub>2</sub> O	0.00	0.340	0.00
Cs <sub>2</sub> S	-0.06	0.251	-0.25
Cs <sub>2</sub> Se	-0.04	0.072	-7.81
Cs <sub>2</sub> Te	-0.07	0.13	-0.51

3 × 6 matrix [16,64,65]:

$$e_{111} = e_{11} = -e_{211} = -e_{112} = e_{22} = -e_{21} = -e_{16}$$
$$= e_{331} = e_{322} = e_{31} = e_{32},$$
$$e_{113} = e_{223} = e_{15} = e_{24},$$

The symmetry analysis reduces the number of independent elastic tensor components:

$$\sigma_{ij} = \sigma_{ji}, \ C_{ijkl} = C_{jikl}, \tag{9}$$

$$\varepsilon_{kl} = \varepsilon_{lk}, C_{ijkl} = C_{ijlk}. \tag{10}$$

Further the strain energy  $U = \frac{1}{2}C_{ijkl} \varepsilon_{ij}\varepsilon_{kl}$  with the property  $\frac{\partial U}{\partial \varepsilon_{ii}} = \sigma_{ij}$  then with all the symmetries:

$$C_{ijkl} = C_{jikl}, \ C_{ijlk} = C_{jilk} \ C_{ijkl} = C_{klij}.$$
(11)

This resulted in a contracted notation  $\sigma_i = C_{ij}\varepsilon_j$ .

From the above representations, the contracted piezoelectric stress and strain tensors are linked by elastic stiffness tensor  $C_{ij}$  as

$$e_{ij} = d_{ik}C_{kj}.\tag{12}$$

The piezoelectric stress and strain coefficients originate from the piezoelectric polarization, i.e., polarization induced upon the application of infinitesimal strain or stress. According to Dong *et al.* [20], in vdW crystals, out-of-plane piezoelectric strain coefficient  $d_{33}$  can be reasonably approximated as

$$d_{33} = \frac{(C_{11} + C_{12})e_{33} - 2C_{13}e_{31}}{(C_{11} + C_{12})C_{33} - 2C_{13}^2} \approx \frac{e_{33}}{C_{33}}.$$
 (13)

The piezoelectric coefficients of the monolayers determined in the out-of-plane direction have been tabulated in Table II. The flexible  $M_2X$  monolayers of the family are found to exhibit small negative out-of-plane piezoelectric stress and strain coefficients  $e_{33}$  and  $d_{33}$ . In the earlier studies, the individual monolayers of the heterostructures BP/GaN

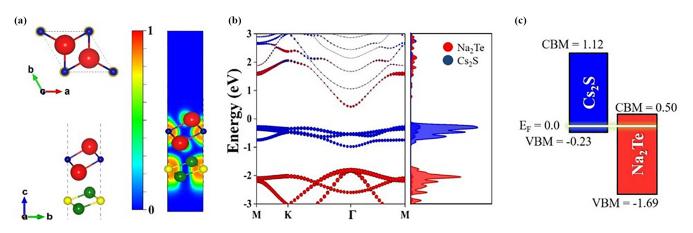


FIG. 3. (a) Top and side views of  $Na_2Te/Cs_2S$  heterobilayer and its electron localization function (ELF) plot. (b) Band structure and density of states plot with individual monolayer contribution to the band dispersion. (c) Band alignment in  $Na_2Te/Cs_2S$  heterobilayer.

[19] and  $In_2Se_3/MoS_2$  [15] showed no or small strength of piezoelectricity along the z direction, but the vdW structures formed witnessed multifold enhancement in piezoelectricity. Thus, with a view to improving upon the piezoresponse of the family of monolayers, 2D type-II vdW heterostructures have been built up by stacking monolayers on top of one another. The vdW heterostructures with lattice mismatch <4% have been investigated for their piezoelectric properties, where the Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure manifested the highest out-of-plane piezoelectric response. The maximum piezoelectric strain response observed in the Na2Te/Cs2S system is  $d_{33} = -39 \text{ pm V}^{-1}$ , respectively. The responses of other heterostructures of the family are shown in Fig. S4 in the SM [51]. The anomalous negative piezoelectric response in heterostructures is scarcely observed. Thus, its origin needs to be elucidated to benefit from this property in future applications. The coming sections are devoted to a thorough investigation of the electronic, mechanical, interfacial charge polarization, electrostatic potential, and piezotronics properties along with the response of the vertical strain and out-of-plane EF applied on the system.

# D. High negative piezoelectricity in Na<sub>2</sub>Te/Cs<sub>2</sub>S vdW heterostructure

#### 1. Geometric and electronic properties

The heterostructure is formed by putting together the individual monolayers vertically in the AA stacking arrangement with the weak vdW interaction holding the monolayers on top of each other. Nearly 3.24% lattice mismatch is found between the individual monolayers in the supercell for the vdW heterostructure, which ensures that the properties of the constituent monolayers are insignificantly altered under this small magnitude of strain. Figure 3(a) provides the top and side views of the optimized heterostructure where the red, blue, yellow, and green spheres represents Cs, S, Te, and Na atoms. The optimized lattice constant and interlayer distance are 5.06 and 2.61 Å, respectively. In the electron localization plot shown in Fig. 3(a), the red 1 represents the 100% electron density, and the blue 0 indicates 0% electron density in the region. The maximum (minimum) electron localization is found to occur on the chalcogen (alkali) atoms, which clearly

depicts the ionic bonding in the intralayer  $Na_2Te$  and  $Cs_2S$  monolayers of the vdW heterostructure.

The electronic band structure of the Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure computed using the PBE functional shows an indirect band gap of 0.73 eV with the CBM and VBM lying at the high-symmetry  $\Gamma$  and M points, respectively. The wellknown underestimation in the band gap by the PBE functional has prompted the use of a more precise HSE06 functional to determine a more accurate band gap of 1.36 eV in the Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure. The band dispersion and DOS presented in Fig. 3(b) show the proper band contribution by the individual monolayers  $Na_2Te$  and  $Cs_2S$ . Figure 3(b) reveals the dominant contribution of the bands of Na<sub>2</sub>Te (Cs<sub>2</sub>S) to the CBM (VBM) band in the heterostructure, thus asserting the type-II band alignment in the system. A comparison in the band structure between the heterostructure and the individual monolayers Na<sub>2</sub>Te and Cs<sub>2</sub>S barely reveals any changes from the constituent monolayers to that in the heterostructure, as shown by Fig. S5 in the SM [51]. It indicates the ability of the individual monolayers to retain their identity while constructing the heterostructure. The band alignment of the monolayers displayed in Fig. 3(c) shows a substantial band offset of 0.6 and 1.4 eV in the CBM and VBM, respectively, in the Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure. The occurrence of a large band offset in the system can imply a vast potential for the application of the layered structure [66]. This much higher band offset among the monolayers would result in an intense interlayer charge polarization and can drive a large out-of-plane piezoelectric response in the heterostructure. In an earlier investigation on the In<sub>2</sub>Se<sub>3</sub>/MoS<sub>2</sub> heterostructure, the enhanced piezoelectricity arose from the large band offset of 0.8 eV between the monolayers of the constituents. However, the independent monolayers exhibited a very low piezoelectric response [15]. Thus, a larger band offset in the Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure is expected to bring in the emerging piezoelectric response through the interface effects between the individual layers.

### 2. Mechanical flexibility and stability

The 2D elastic moduli of the vdW  $Na_2Te/Cs_2S$  heterobilayer are shown in Table III. The magnitude of in-plane

TABLE III. The elastic stiffness constants, Young's modulus (Y), Poisson's ratio (v), and bending modulus (D) of the heterostructure.

Heterostructure	$C_{11} = C_{22}$	$C_{12}$	$C_{66} = G$	<i>C</i> <sub>33</sub>	$Y (N m^{-1})$	υ	D (eV)	Status
Na <sub>2</sub> Te/Cs <sub>2</sub> S	26.54	9.87	7.28	2.56	22.86	0.37	8.83	Stable

elastic moduli  $C_{11}$  in a vdW bilayer is observed to be close to the sum of the elastic moduli of the constituent monolayers. The  $C_{11}$  moduli in the heterobilayer is usually lower [59,67– 69] or higher [70–73] than the sum of the individual ones depending upon the strength of the vdW interaction between the monolayers, which is quantifiable via the out-of-plane elastic constant  $C_{33}$ . The interlayer coupling at the interface of layers stacked by the vdW interaction enhances  $C_{33}$  in the bilayer relative to the individual monolayers [74,75], as given in Table IV. Also, by varying the interlayer distance, its effects on in-plane and out-of-plane elastic constants have been understood, as given in Table S2 in the SM [51]. The interlayer coupling or interaction clearly increases with the decrease in interlayer distance, which evidently shows up in the increases in  $C_{33}$  and, in turn, a higher in-plane elastic constant, i.e.,  $C_{11}$ . The Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure meets all the Born-Huang elastic stability criteria for the hexagonal system, i.e.,  $C_{11} > |C_{12}|, C_{22} > 0, C_{11}C_{22} - C_{12}^2 > 0$ , and  $C_{66} > 0$ :

$$Y_{2D} = \frac{C_{11}^2 - C_{12}^2}{C_{11}}; \quad \upsilon = \frac{C_{12}}{C_{11}}; \quad G = C_{66}; \quad D = \frac{Yh^2}{12(1-\upsilon^2)}.$$
(14)

The in-plane static Young's modulus (*Y*) is of lesser order than that of the numerous flexible monolayers [76,77]. Also, the bending modulus is comparable with monolayer WSe<sub>2</sub> (D = 8.5 eV) [78] and MoS<sub>2</sub> [79], affirming the robust mechanical properties of the heterostructure.

To determine any anisotropy present in the vdW heterobilayer (vdWH), the area modulus ( $K^V$  and  $K^R$ ) and shear modulus ( $G^V$  and  $G^R$ ) have been calculated using the Voigt and Reuss estimation by the following formulas [80]:

$$\mathbf{K}^{\mathbf{V}} = \frac{C_{11} + C_{22} + 2C_{12}}{4},\tag{15}$$

$$\mathbf{K}^{\mathbf{R}} = \frac{1}{S_{11} + S_{22} + 2S_{12}},\tag{16}$$

$$G^{V} = \frac{C_{11} + C_{22} - 2C_{12} + 4C_{66}}{8},$$
 (17)

$$\mathbf{G}^{\mathbf{R}} = \frac{2}{S_{11} + S_{22} - 2S_{12} + S_{66}},\tag{18}$$

TABLE IV. Piezoelectric stress coefficient ( $e_{33}$ ), elastic stiffness constants ( $C_{33}$ ), and out-of-plane piezoelectric strain coefficient ( $d_{33}$ ) of Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure. The units of  $e_{il}$ ,  $C_{ij}$ , and  $d_{il}$  are pC m<sup>-1</sup>, N m<sup>-1</sup>, and pm V<sup>-1</sup>, respectively.

Material	<i>e</i> <sub>33</sub>	<i>C</i> <sub>33</sub>	<i>d</i> <sub>33</sub>
$Na_2Te/Cs_2S$ heterobilayer	-59.68	2.56	-39.89
Cs <sub>2</sub> S bilayer Na <sub>2</sub> Te bilayer	-16.43 -4.342	8.35 3.15	-2.028 -1.92

where  $C_{ij}$  are elastic stiffness constants,  $S_{ij}$  are compliance matrices defined as  $S = C^{-1}$ . The calculated area and shear modulus are estimated to be  $K^V = 18.21 \text{ eV}$ ,  $K^R = 18.28 \text{ eV}$ ,  $G^V = 7.81 \text{ eV}$ , and  $G^R = 7.73 \text{ eV}$ . The elastic anisotropy index indicating the degree of anisotropy in the system has been determined from the area and shear modulus using the following relation:

$$A^{SR} = \sqrt{\left(\frac{K^{V}}{K^{R}} - 1\right)^{2} + 2\left(\frac{G^{V}}{G^{R}} - 1\right)^{2}}.$$
 (19)

The A<sup>SR</sup> comes out to be 0.014 which is extremely close to zero. The minimum value of the elastic anisotropy index for an isotropic system can reach zero in the case of perfect mechanical isotropy in the system. Thus, the vdWH has been found to retain isotropic elastic properties in the individual monolayers.

# 3. Electrostatic potential and interfacial charge transfer in 2D layered heterostructure

Despite weak vdW contact within the stacked monolayers, there lies possibilities for interlayer charge exchange or polarization, either due to the small interlayer spacing/gap or high electronegativity difference between the individual layers. To shed light on the interfacial properties of the heterostructure, the electrostatic potential and interfacial electrostatic charge distribution have been explored. The average electrostatic potential of the individual monolayers and the heterostructure Na<sub>2</sub>Te/Cs<sub>2</sub>S has been calculated in an absolute vacuum scale, as shown in the Fig. 4. The potential plot of the constituent monolayers relative to the constructed heterobilayer hardly indicates any difference, owing to the weak vdW interaction existing between the individual monolayers. The difference in electrostatic potential between the heterostructure and the sum of the potential of the two monolayers is indicated by potential energy difference  $\Delta V$  at the interface, which brings about the built-in EF. The deformation charge density or the planar averaged charge density difference  $(\Delta \rho)$  can quickly unveil the electronic charge redistribution across the monolayers using following formalism [81]:

$$\Delta \rho = \int \rho_{\text{Na}_2\text{Te}/\text{Cs}_2\text{Te}}(x, y, z) dx dy - \int \rho_{\text{Na}_2\text{Te}}(x, y, z) dx dy - \int \rho_{\text{Cs}_2\text{Te}}(x, y, z) dx dy,$$
(20)

where  $\rho$  is the plane averaged charge density of the vdWH and monolayers. The oscillating deformation charge density  $(\Delta \rho)$  or the alternating spatial charge accumulation and depletion, shown in Fig. 4(b), indicates the charge polarization, instigated by the built-in EF in the system. On average, Na<sub>2</sub>Te and Cs<sub>2</sub>S monolayers get negatively (in red) and positively (in green) charged by the vdW interactions. The extent of charge acquired/transferred has been quantified by the integration

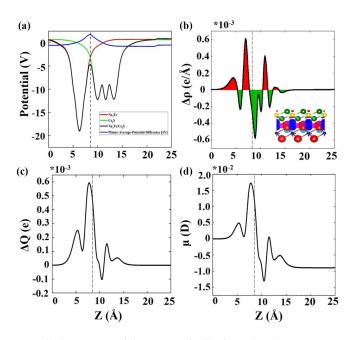


FIG. 4. (a) Potential energy distribution. (b) Plane-averaged charge density difference. Here, the oscillations show depletion and accumulation (in green and red) of electronic charge density, and the inset three-dimensional (3D) isosurface of charge density difference. (c) Total charge transferred. (d) Interfacial dipole moment  $\mu$  in the normal plane of the Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure.

of the charge density difference as  $\Delta Q = \int_{-\infty}^{Z} \Delta \rho(z') dz'$ , where  $\Delta \rho$  is the planar average charge density difference for the heterostructure. From Fig. 4(c), the Na<sub>2</sub>Te monolayer is observed gaining  $\Delta Q = |0.015|e$  charge from the Cs<sub>2</sub>S layer. The small degree of charge transfer or polarization confirms the weak character of the vdW interaction. Further, the interface-induced dipole moment by the charge transfer has been determined using  $\mu = \int_{-\infty}^{Z} z\Delta \rho(z') dz'$ . Formation of the dipole moment of -0.008 D strength in the heterostructure is observed, where the negative values of  $\mu$  suggest the outward pointing dipole [82], that is, from Na<sub>2</sub>Te to Cs<sub>2</sub>S monolayer. The development of large electrostatic potential energy difference, oscillating deformation charge density, and built-in interfacial dipole moment in the z direction will assuredly lead to out-of-plane polarization and resultant outof-plane piezoelectric coefficient in the heterostructure.

#### 4. Piezoelectricity

The piezoelectric stress and strain coefficients for the heterobilayer Na<sub>2</sub>Te/Cs<sub>2</sub>S have come out to be  $e_{33} = -200.8 \text{ pC m}^{-1}$  and  $d_{33} = -39 \text{ pm V}^{-1}$ , respectively. The interface effects in vdW bilayers enhance the piezoelectric coefficient  $d_{33}$  with respect to the individual monolayers [15,19,83,84]. In addition, the variation in piezoelectric response with different stacking arrangements by rotating one monolayer about another at angles of 0°, 60°, 120°, and 180° is shown in Fig. S8 and thoroughly discussed in the SM [51]. Further, to observe the heterostructure vs the influence of layering, piezoelectric studies have been carried out on individual bilayers of Na<sub>2</sub>Te and Cs<sub>2</sub>S, where interfacial characteristics comprising electrostatic potential, planar averaged

charge density, charge transfer, and development of the dipole moment at the interface have been computed, as shown in Figs. S6 and S7 in the SM [51]. In both homobilayers and heterobilayers of Na<sub>2</sub>Te and Cs<sub>2</sub>S, the elastic stiffness  $C_{33}$  is noted to be higher than the individual monolayers, as given in Table IV, due to the presence of the vdW interactions at the interface which is common in layers stacked via weak vdW interactions [74,75].

Then the piezoelectric coefficients ( $e_{33}$  and  $d_{33}$ ) are found to be enhanced in the bilayers and heterostructure with respect to the individual monolayers due to interface effects (i.e., through the development of interfacial dipoles) [19,31–34]. As the charge transfer and polarization (electronic dipole) arises at the interface, as marked with the dashed line in Figs. 4 and S6 and S7 in the SM [51], piezoelectricity increases correspondingly in bilayer Na<sub>2</sub>Te, bilayer Cs<sub>2</sub>S, and the Na<sub>2</sub>Te/Cs<sub>2</sub>S heterobilayer, depending on the sensitivity of the interfacial polarization to the application of infinitesimal stress or strain, as calculated using DFPT. The maximum piezoelectric stress and strain coefficients in the Na<sub>2</sub>Te/Cs<sub>2</sub>S bilayer are apparently caused by its smaller  $C_{33}$  and higher interfacial charge polarization relative to the other bilayers. The higher charge polarization is brought about by a higher  $\Delta V$ and is indicated by higher charge transfer ( $\Delta Q$ ) and higher interfacial dipole moment  $(\mu)$  at the interface, i.e., in the neighborhood of the vertical dotted lines in Figs. 4 and S6 and S7 in the SM [51]. Finally, it is the piezoelectric polarization and not the intrinsic polarization which is responsible for the piezoelectric constants obtained through DFPT calculations in this paper. The change in polarization under infinitesimal stress or strain, i.e., piezoelectric polarization, is understood to be higher in the heterobilayer than the homobilayers, as confirmed by the higher values of  $e_{33}$  and  $d_{33}$  obtained from the DFPT calculations.

In a strong out-of-plane piezoelectric coefficient, its sign should not be neglected. The anomalous negative piezoelectricity in the heterostructure can bring about an uncommon response, leading to the interlayer compression along the direction of the applied EF, as opposed to the usual crystal expansion in a material having positive piezoelectric coefficient. A thorough investigation of the heterostructure will determine the origin of such anomalous behavior in the system. To probe the nature of the vdW interaction, the in-plane stress induced in the heterostructure by vertical compressive strain has been examined, as shown Fig. 5(a). The linear fit to the stress-strain curve in the range of 3% strain has given the out-of-plane Young's modulus to be  $11 \text{ N m}^{-1}$ . The extremely small Young's modulus is in sync with the small out-of-plane elastic constant  $C_{33}$ . Hereafter, the impact of strain on interlayer vdW distance d and intralayer thickness ghas been plotted in Fig. 5(b). The larger influence on intralayer vdW distance d relative to ionically bonded intramonolayer thickness g with strain is found in the heterostructure, which appears due to the soft vdW interaction in the system. The ferroelectric polymer PVDF and its copolymers, which condense through the weak van der Waal interaction, exhibit negative piezoelectricity. In experimental and theoretically examined 2D CuInP<sub>2</sub>S<sub>6</sub>, the free movement of Cu ion and the soft interaction offer large deformation under EF and bring out negative piezoelectricity in the system. The anomalous negative

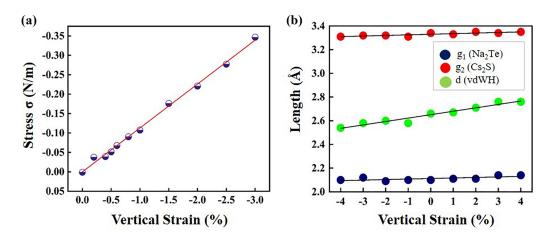


FIG. 5. (a) Stress-to-strain plot under vertical compressive strain. (b) Change in layer thickness  $g_1$  (Na-Na),  $g_2$  (Cs-Cs), and interlayer van der Waals distance d (Na<sub>2</sub>Te-Cs<sub>2</sub>S) with the vertical compressive and tensile strain.

piezoelectric responses in the Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure have stemmed from the small Young's modulus, elastic constant  $C_{33}$ , and the soft interactions at the interface. This unconventional piezoelectric coefficient in the heterostructure will establish applications in futuristic electromechanical piezoelectric devices at the nanoscale.

#### 5. Vertical compressive strain

The application of vertical compressive strain is an effectual mean to vary the electronic band spectra of 2D systems. The earlier studies on graphene [85], MoTe<sub>2</sub>, WTe<sub>2</sub> monolayers, and their heterostructures [86] have shown the band gap opening under compressive strain. The application of strain by changing interlayer equilibrium distance significantly varies the interlayer interaction in the heterostructure and modifies the electronic properties of the system. By reducing the interlayer gap in the heterostructure, the Coulombic repulsion between the individual layers sets in first, which increases progressively and results in the change in electronic properties like band structure and band gap attenuation. Here, the investigation has been conducted on the heterostructure Na<sub>2</sub>Te/Cs<sub>2</sub>S to observe the influence of strain on the electronic properties of the system. Interlayer gap smaller than the equilibrium interlayer distance  $d_0$  turns the binding energy of the heterostructure positive and thus brings it to the repulsive regime, which can be seen in Fig. 6(a). The increasing interlayer distance beyond  $d > d_0 = 2.61$  Å results in band gap reduction, while the decreasing interlayer distance  $d < d_0$ enlarges the band gap. The increasing binding energy or the interlayer Coulomb repulsion together with the hybridization of orbitals from each layer by vertical compressive strain causes the increase in band gap in the heterostructure which is comparable with the earlier findings on the heterostructures C<sub>2</sub>N/MoS<sub>2</sub> [87], graphene/PtSe<sub>2</sub> [88], and graphene/MgS [48]. The band dispersion clearly displays the movement of the energy band with the strain. In the Figs. 6(b) and 6(c), the electronic band structures at the interlayer gap  $d-d_0 = 0.6$ and -0.6 Å has been shown where the influence of the strain is clearly discernible at the CBM of the heterostructure, which induces the modulation in band gap. The work function and band alignment along the side undergo some changes under

vertical strain. The CBM moves up (down) upon decreasing (increasing) the interlayer distance. However, the type-II band alignment arising from CBM (VBM) contributed by Na<sub>2</sub>Te (Cs<sub>2</sub>S) monolayers is found to be retained even at the highest level of vertical strain studied in this paper. The work function is a bit sensitive to the application of interlayer distance, as tabulated in Table S2 in the SM [51], where compressive (tensile) strain is found to increase (decrease) the work function. Additionally, the magnitude of the planar average electrostatic potential rises (falls) at the interlayer region upon decrease (increase) in interplanar spacing/distance. As a result, it induces a higher (smaller) charge polarization and dipole under compression (expansion) of the interlayer distance. Consequently, the difference in charge density shows a similar trend and is consistent with the behavior in work function. Figure S9 in the SM [51] shows the planar-averaged electrostatic potential energy distribution, the plane-averaged charge density difference, total charge transferred, and the interfacial dipole moment  $\mu$  for the Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure with the change in interlayer distance  $(d - d_0 = -0.6, 0, \text{ and } 0.6 \text{ Å})$ . This band gap tunability via the applied vertical strain can in fact present greater opportunities for the heterostructure in the fields of nanoelectronics, piezotronics, optoelectronics, etc.

#### 6. External EF

(a) Energy band diagrams. External EF on a lowdimensional material is hot stream work and is seen bringing huge improvements to the electronic properties of the systems. Experimentally, multilayer MoS<sub>2</sub> has been reported, showing the transition in the band gap from indirect to direct with the EF. Other monolayers, for instance,  $MX_2$  (M = Mo or W; and X = S, Se, or Te) [89], MgTe [14], Janus SnSSe [90], heterostructure SiC/BN [91], and  $\alpha$ -P/H-MoS<sub>2</sub> [92], have come up with band gap closing by EF. The evaluation of the band gap in the presence of an EF is a vital investigation that should be conducted to forecast the potential of 2D systems in low-powered devices.

The EF effects on the Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure have been investigated to study the electronic property modulation in the system. The field is applied normal to the plane in the range of +0.4 to -0.4 V/Å. The equilibrium structure is

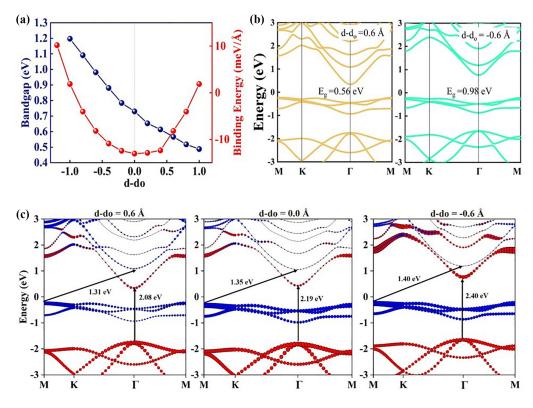


FIG. 6. (a) Change in band gap and binding energy of Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure with the change in interlayer distance from equilibrium. (b) Band structure evolution in Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure at the changed interlayer distance  $d-d_0 = 0.6$  and -0.6 Å. (c) Band dispersion under strain showing the contribution of Na<sub>2</sub>Te (red) and Cs<sub>2</sub>S (blue) monolayers.

preserved throughout the application of the EF. The electronic structure evolution with the EF, shown in Fig. 7(a), exhibits a decrease in band gap with the increasing EF strength. The band gap falls gradually with the negative EF and reaches zero at the field strength of -0.33 V/Å, while for the positive EF, it initially increases up to 0.88 eV and then starts decreasing and completely closes at +0.31 V/Å field. At high EFs (0.31 and -0.33 V/Å), minor change occurs upon structural relaxation, which has been tabulated in Table S3 in the SM [51]. At the applied EF of 0.31 V/Å, the interlayer distance changes by only 0.48 Å. The band structure is hardly found to be altered by this structural change under the applied vertical EF of 0.31 V/Å. A slight change in the band gap is noted upon relaxing the structures, as follows. The EF (along the zdirection) needed for closing the band gap is found to increase only by 0.03 V/Å. While the band gap is unaffected by an EF of magnitude -0.33 V/ applied along the -z direction. A comparative study of the relaxed and unrelaxed structures under the influence of the EF, as plotted in Fig. S10 in the SM [51], hardly shows any difference in the band structures. It clearly indicates that the underlying physics does not change from the unrelaxed to the relaxed structure at the high value of EF  $\sim 0.3 \text{ V/Å}$ .

A gradual transition from semiconduction to metallization in the vdWH by the EF along both directions can purposely serve the heterostructure in the field of digital electronics. As at zero EF, the heterostructure is semiconducting with high resistance and low tunneling current (OFF state), whereas at critical EF of +0.31/-0.33 V/Å, it is metallic with low resistance and high tunneling current (ON state). The output response can be simply tuned from ON to OFF state (1 to 0) and vice versa through a low gate voltage. In Fig. 7(c), a schematic of the ON/OFF state with the pulsed input voltage has been presented. Like this, the heterostructure can be considered for data storage device applications where gate voltage can easily control the output signal.

On visualizing the band spectra, the change in the band gap from the semiconducting to the metallic state is clearly visible to be driven by the NFEG bands in the Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure. The blue, red, and black bands show the Cs<sub>2</sub>S, Na<sub>2</sub>Te, and NFEG bands in the electronic dispersion in Fig. 7(a). The NFEG states are the unoccupied surface states on the 2D materials with nearly free electronlike characteristics. As these states are extremely sensitive to external perturbations, it can be brought down to around the Fermi level via the effect of EF or surface functionalization [29,93,94] and then used advantageously in surface catalysis, sensing, and increasing the electrical conductivity of the heterostructure [95]. Any possible errors occurring in the energetic position and spatial location of these states in the presence of an EF can be addressed through the application of the periodic boundary condition together with a dipole correction term [45], as employed in this paper. However, in this paper, the NFEG states are visible in the single-layer Cs<sub>2</sub>S monolayer even when no EF is applied. The occurrence of NFEG states in the single layer of Cs<sub>2</sub>S even in the absence of an applied EF completely rules out the possibility of computational artifacts in the emergence of these states. Figure S13 and the discussion that follows it in the SM [51] support this argument assertively. In this paper, we demonstrate

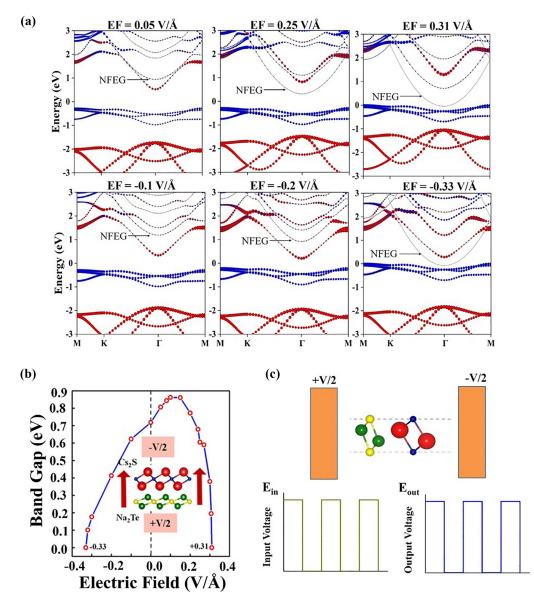


FIG. 7. (a) Band dispersion under the application of positive and negative out-of-plane electric field [EF; the nearly free electron gas (NFEG) states have been indicated by arrows]. (b) Band gap modulation via the EF for the heterostructure. (c) Schematics illustration of the application of out-of-plane EF and electric output response by modulating the electric input.

unequivocally that the NFEG states are truly physical and not artifacts of the calculations, as has been observed theoretically and experimentally in certain other 2D systems [29,30,32,96–98].

From Fig. 7(a), the dominance of the NFEG bands with the increasing EF in either direction can be grasped. They overshoot the CBM at a higher field strength and ultimately fall to the Fermi level, resulting in zero band gap of the heterostructure. To investigate the response of NFEG states to an applied EF, the electronic band structure at different field strengths around the high-symmetry  $\Gamma$  point has been depicted in Fig. S11 in the SM [51]. The NFEG band, which is a conduction band, as marked by arrows in Fig. S11 in the SM [51], evolves with positive and negative EF. The spatial distribution of the NFEG states in the Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure, shown in Fig. S12 in the SM [51], is given by the band-decomposed charge density at the  $\Gamma$  point in the marked conduction band in Fig. S11 in the SM [51]. The NFEG charge density peak is observed close to the Cs<sub>2</sub>S monolayer in the absence of applied EF, which is consistent with the contribution of the Cs<sub>2</sub>S monolayer to the NFEG states at zero EF, as supported by the atom projected band structure of the NFEG band. It is like the contribution of hydrogen atoms to NFEG states in  $Hf_2C(OH)_2$  [29]. Upon the application of EF of progressively increasing strength to the heterostructure, the NFEG state density is found to shift away to the vacuum region for both positive and negative EFs, and consequently, the contribution of the Cs<sub>2</sub>S monolayer to the NFEG band gradually drops off and vanishes for both positive and negative EFs, as evident from the atom projected band structure. The trend is found to be the same for both positive and negative EFs. The dropping of the NFEG states upon the application of an EF has been noticed in a bilaver InSe [31]. Also, Shibuta et al. [99] studied the NFEG bands

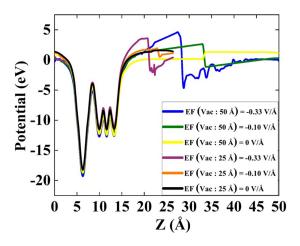


FIG. 8. Change in electrostatic potential with applied electric field at vacuum thicknesses of 25 and 50 Å.

above the Fermi level, where they observed a pronounced charge transfer on the lowering of these bands. Interestingly, in MoSSe/BP and InSe/BP heterobilayers [49,84], the results vary from the current heterostructure. On the application of positive and negative EFs, the bands of the individual monolayers move along opposite directions to close the band gap at unequal magnitudes of positive and negative EFs [49,84]. MoSSe/BP does not show NFEG states, while the response of the conduction band edge in InSe/BP masks the NFEG states. Clearly, the electronic structure and electrostatic potential in Na<sub>2</sub>Te/Cs<sub>2</sub>S are different, where under the action of both positive and negative EFs, the NFEG states descend to the Fermi level and the valence band edge to close the band gap.

(b) Electrostatic potential. As the external EF contributes a linear potential, it is important to study the variation in the electrostatic potential in the heterostructure with applied EF. Figure S14 in the SM [51] depicts the changes in the electrostatic potential with applied EF of varying strengths.

Since the vacuum thickness has been shown to play a role in the closure of band gap via the application of an EF [30], vacuum thicknesses of 25 and 50 Å have been employed in this paper.

For a fixed vacuum thickness, the spatial extent of the linear potential contributed by the external EF decreases, while the slope of this linear potential is found to increase with the magnitude of the applied EF, as shown by Fig. 8. Again, upon increasing the vacuum thickness for a fixed EF, the spatial extent of the linear potential is only found to increase, as evident from Fig. 9. The change in the linear potential induces the observed spatial shift in the NFEG states (marked in Fig. S16 in the SM [51]) with vacuum thickness and applied EF, as shown in Fig. S15 in the SM [51], consistent with Figs. 8 and 9. The NFEG states are also found to shift down in energy with increased vacuum thickness. Then increasing the vacuum thickness is found to lower the EF required to close the band gap, as shown in Fig. S16 in the SM [51], which conforms to an earlier finding by Zhou et al. [30]. Moreover, to check the sensitivity of results to the vacuum thickness, the unrelaxed and relaxed structures at 50 Å vacuum thickness are compared systematically with that of 25 Å vacuum thickness, as shown in Fig. S17 in the SM [51]. In conformance with

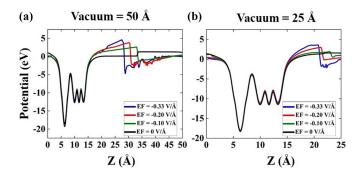


FIG. 9. Electrostatic potential as a function of applied electric field in Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure with a vacuum thickness (a) 50 Å and (b) 25 Å.

an earlier study [30], a higher vacuum thickness is found to close the band gap at a smaller EF. As shown in Fig. S17 in the SM [51], the EF needed to close the band gap drops down appreciably upon increasing the vacuum thickness. Further, relaxation is not found to cause a major change in the band structure and the EF required to close the band gap, which is like the earlier observations noted at 25 Å vacuum thickness, as projected in Fig. S17 in the SM [51]. At 50 Å vacuum thickness, the band gap is closed at -0.21 (-0.23) V/Å and 0.19 (0.225) V/Å of positive and negative EFs, respectively, in the unrelaxed (relaxed) structures, while with 25 Å vacuum thickness, the band gap closed at -0.33 (-0.33) V/Å and 0.31 (0.34) V/Å for positive and negative EFs, respectively, in unrelaxed (relaxed) structures. Interestingly, the interlayer relaxation reduces drastically to a negligible level upon raising the vacuum thickness to 50 Å. Interlayer relaxation of 0.48 and 0.02 Å noticed at 25 Å vacuum thickness (under the application of positive and negative applied EFs, respectively) drops to 0.09 and 0.01 Å at 50 Å vacuum thickness. Table S3 in the SM [51] lists the bond lengths and interlayer distances for both unrelaxed and relaxed structures at the two vacuum thicknesses.

As noted in the preceding subsections, the same trend is shown by both positive and negative EFs. Likewise, the electrostatic potential exhibits a similar pattern with a positive EF, which is shown in Fig. S14 in the SM [51].

(c) Electrical conductivity. As most electronic devices are integrated with gate voltage, the population/density of charge carriers in the system can be controllably moderated via gating. The increased population/density of carriers can enhance the response in terms of electrical current or conductivity immensely in the system. The study on  $MX_2$  (TMDC) monolayers has shown a large effect of the EF on transport properties of the monolayers [94]. Thus, with the NFEG bands in the Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure, it is expected to have a significant improvement in the electrical conductivity. In Fig. 10, the variation of electrical conductivity with the EF along the positive and negative z direction has been shown where the negative (yellow) and positive (green)  $\mu = (E - E_F)$  represent the p- and n-type regions of the vdWH.

The electrical conductivities in p- and n-type regions show different EF responses, which is consistent with the faster movement of the conduction bands toward the Fermi level than that of the valence bands, as noted in Fig. 7. The electrical

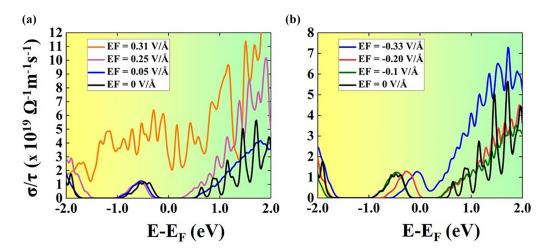


FIG. 10. Change in electrical conductivity of Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure with applied electric field (along both directions) at the temperature T = 300 K. The right (green) region for  $E - E_F > 0$  represents *n*-type conductivity, and the left (yellow) region corresponding to  $E - E_F < 0$  represents *p*-type conductivity.

conductivity is not very enhanced near the valence band by increasing the EF along any direction, while for the near conduction band region (i.e., for positive chemical potential), conductivity drops at first under a small EF. This fall in the electrical conductivity has resulted from the increased collisional effect or scattering phenomena upon the introduction of EF [95]. However, as the EF increases and the heterostructure reaches toward the metallization, the conductivity shows a sharp boost. The increment in the electrical conductivity is clearly reflected from the increased electronic DOS observed in Fig. S18 in the SM [51]. From the DOS plot, it is observed that the charge density increases immensely at the EF of 0.31 V/Å and thereby results in an enhanced electrical conductivity of the heterostructure. This overlays the way for the development of the Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure-based nanoelectronic devices for futuristic applications.

#### **IV. CONCLUSIONS**

Ab initio investigations on the electronic, mechanical, and the piezotronic properties of the family of 2D dialkali metal monochalcogenide  $M_2X$  monolayers have been carried out systematically, which reveal a semiconducting band gap in the monolayers and low piezoelectric strain coefficients  $d_{33} \sim$ -0.5 to +2.0 pm V<sup>-1</sup> along with extreme flexibility, attested by small Young's modulus  $Y \sim 50$  to  $8 \text{ N m}^{-1}$ . The heterostructures formed from the family of monolayers have led to significant improvement in the negative out-of-plane piezoelectricity with the highest longitudinal negative piezoelectric coefficient  $d_{33} = -39$  pm V<sup>-1</sup> found in the Na<sub>2</sub>Te/Cs<sub>2</sub>S heterostructure. The rise in the piezoelectric coefficient  $d_{33}$  in this specific heterostructure has been seen to appear due to the large band offset of  $\sim 0.6$ –1.4 eV and electrostatic potential energy difference among the layers. The out-of-plane dipole moment that builds up in the heterostructure is -0.008 D. The anomalous nature of the negative piezoelectric property owes its origin to the very small out-of-plane elastic stiffness

and Young's modulus, which is brought up by the weak vdW interlayer interactions. It is analogous to the layered structure of CuInP<sub>2</sub>S<sub>6</sub> investigated earlier. The soft interactions at the interface have been affirmed by the small out-ofplane Young's modulus ( $Y \sim 11 \text{ N m}^{-1}$ ). The small in-plane  $(Y \sim 22 \text{ N m}^{-1})$  and out-of-plane  $(Y \sim 11 \text{ N m}^{-1})$  flexibilities mark the heterostructure as a superior material for flexible electronics devices. The prominent response to the external stimuli, i.e., the vertical strain and EF, is observed to modulate the electronic properties of the heterostructure. The vertical compressive strain causes the band gap enlarging, while vertical EF induces the gradual narrowing and closure of the band gap, bringing the semiconducting-to-metallic transition at a low EF of 0.31 and -0.33 V/Å. The latter results in a high DOS close to the Fermi level as the result of shifting of the NFEG bands and conduction band edge moving to the Fermi level. The presence of these high density of surface states near the Fermi level largely boosts the charge carrier transport and electrical conductivity. Low-power-consumption data storage devices can be envisioned based on the proposed vdWH, where the device can be turned from OFF to ON state and vice versa via small gate voltage. Moreover, the highly negative piezoelectric properties together with perturbationinduced tunability in electrical conductivity can be effectively utilized in piezotronics devices and next-generation electronic devices.

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